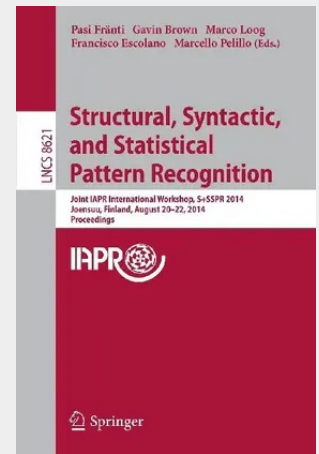


Structural, Syntactic, and Statistical Pattern Recognition

Joint IAPR International Workshop, S+SSPR 2014, Joensuu, Finland, August 20-22, 2014, Proceedings

This book constitutes the proceedings of the Joint IAPR International Workshop on Structural, Syntactic, and Statistical Pattern Recognition, S+SSPR 2014; comprising the International Workshop on Structural and Syntactic Pattern Recognition, SSPR, and the International Workshop on Statistical Techniques in Pattern Recognition, SPR. The total of 25 full papers and 22 poster papers included in this book were carefully reviewed and selected from 78 submissions. They are organized in topical sections named: graph kernels; clustering; graph edit distance; graph models and embedding; discriminant analysis; combining and selecting; joint session; metrics and dissimilarities; applications; partial supervision; and poster session.

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